

**BFU520W** NPN wideband silicon RF transistor Rev. 1 – 13 January 2014

**Product data sheet** 

### 1. Product profile

### 1.1 General description

NPN silicon RF transistor for high speed, low noise applications in a plastic, 3-pin SOT323 package.

The BFU520W is part of the BFU5 family of transistors, suitable for small signal to medium power applications up to 2 GHz.

#### 1.2 Features and benefits

- Low noise, high breakdown RF transistor
- AEC-Q101 qualified
- Minimum noise figure (NF<sub>min</sub>) = 0.6 dB at 900 MHz
- Maximum stable gain 18.5 dB at 900 MHz
- 11 GHz f<sub>T</sub> silicon technology

### **1.3 Applications**

- Applications requiring high supply voltages and high breakdown voltages
- Broadband amplifiers up to 2 GHz
- Low noise amplifiers for ISM applications
- ISM band oscillators

#### 1.4 Quick reference data

#### Table 1. Quick reference data

#### $T_{amb} = 25 \ ^{\circ}C$ unless otherwise specified

· anno =•		-					
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>CB</sub>	collector-base voltage	open emitter		-	-	24	V
$V_{CE}$	collector-emitter voltage	open base		-	-	12	V
		shorted base		-	-	24	V
$V_{EB}$	emitter-base voltage	open collector		-	-	2	V
I <sub>C</sub>	collector current			-	5	30	mA
P <sub>tot</sub>	total power dissipation	$T_{sp} \le 87 \ ^{\circ}C$	<u>[1]</u>	-	-	450	mW
h <sub>FE</sub>	DC current gain	$I_{C} = 5 \text{ mA}; V_{CE} = 8 \text{ V}$		60	95	200	
C <sub>c</sub>	collector capacitance	V <sub>CB</sub> = 8 V; f = 1 MHz		-	0.55	-	pF
f <sub>T</sub>	transition frequency	$I_{C}$ = 10 mA; $V_{CE}$ = 8 V; f = 900 MHz		-	10	-	GHz



#### NPN wideband silicon RF transistor

Table 1.Quick reference datacontinued $T_{amb} = 25 \ ^{\circ}C$ unless otherwise specified							
Symbol	Parameter	Conditions	Μ	lin	Тур	Мах	Unit
G <sub>p(max)</sub>	maximum power gain	$I_{C}$ = 5 mA; $V_{CE}$ = 8 V; f = 900 MHz	[2] _		18.5	-	dB
$NF_{min}$	minimum noise figure	$I_{C}$ = 1 mA; $V_{CE}$ = 8 V; f = 900 MHz; $\Gamma_{S}$ = $\Gamma_{opt}$	-		0.6	-	dB
P <sub>L(1dB)</sub>	output power at 1 dB gain compression	$I_C$ = 10 mA; $V_{CE}$ = 8 V; $Z_S$ = $Z_L$ = 50 Ω; f = 900 MHz	-		7.0	-	dBm

[1]  $T_{sp}$  is the temperature at the solder point of the collector lead.

If K > 1 then  $G_{p(max)}$  is the maximum power gain. If K < 1 then  $G_{p(max)}$  = MSG. [2]

#### **Pinning information** 2.

Table 2.	Discrete pinning	
Pin	Description	Simplified outline Graphic symbol
1	base	
2	emitter	
3	collector	1 2 2 aaa-010458

#### **Ordering information** 3.

#### Table 3. **Ordering information**

Type number	Packag	e	
	Name	Description	Version
BFU520W	-	plastic surface-mounted package; 3 leads	SOT323
OM7960	-	Customer evaluation kit for BFU520W, BFU530W and BFU550W [1]	-

[1] The customer evaluation kit contains the following:

a) Unpopulated RF amplifier Printed-Circuit Board (PCB)

b) Unpopulated RF amplifier Printed-Circuit Board (PCB) with emitter degeneration

- c) Four SMA connectors for fitting unpopulated Printed-Circuit Board (PCB)
- d) BFU520W, BFU530W and BFU550W samples

e) USB stick with data sheets, application notes, models, S-parameter and noise files

#### 4. Marking

Table 4. Marking		
Type number	Marking	Description
BFU520W	ZA*	* = t : made in Malaysia
		* = w : made in China

BFU520W **Product data sheet** 

#### NPN wideband silicon RF transistor

### 5. Design support

Table 5. Available design support   Download from the BFU520W product inform	ation page on <u>I</u>	nttp://www.nxp.com.
Support item	Available	Remarks
Device models for Agilent EEsof EDA ADS	yes	Based on Mextram device model.
SPICE model	yes	Based on Gummel-Poon device model.
S-parameters	yes	
Noise parameters	yes	
Customer evaluation kit	yes	See Section 3 and Section 10.
Solder pattern	yes	
Application notes	yes	See Section 10.1 and Section 10.2.

## 6. Limiting values

#### Table 6.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
		Conditions			
V <sub>CB</sub>	collector-base voltage	open emitter	-	30	V
$V_{CE}$	collector-emitter voltage	open base	-	16	V
		shorted base	-	30	V
$V_{EB}$	emitter-base voltage	open collector	-	3	V
I <sub>C</sub>	collector current		-	50	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
V <sub>ESD</sub>	electrostatic discharge voltage	Human Body Model (HBM) According to JEDEC standard 22-A114E	-	±150	V
		Charged Device Model (CDM) According to JEDEC standard 22-C101B	-	±2	kV

## 7. Recommended operating conditions

Table 7.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>CB</sub>	collector-base voltage	open emitter	-	-	24	V
V <sub>CE</sub>	collector-emitter voltage	open base	-	-	12	V
		shorted base	-	-	24	V
$V_{EB}$	emitter-base voltage	open collector	-	-	2	V
I <sub>C</sub>	collector current		-	-	30	mA
Pi	input power	Z <sub>S</sub> = 50 Ω	-	-	10	dBm
Tj	junction temperature		-40	-	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{sp} \le 87 \ ^{\circ}C$	<u>[1]</u> _	-	450	mW

[1]  $T_{sp}$  is the temperature at the solder point of the collector lead.

### 8. Thermal characteristics

Table 8.	Thermal characteristics			
Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point		<u>[1]</u> 140	K/W

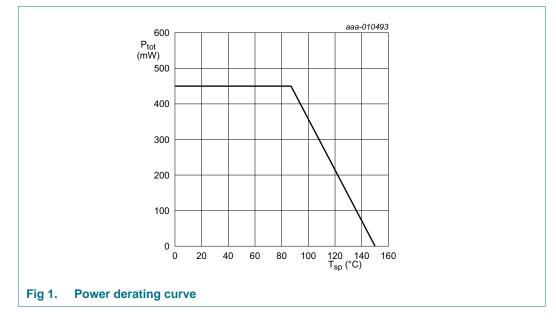
[1]  $T_{sp}$  is the temperature at the solder point of the collector lead.

 $T_{sp}$  has the following relation to the ambient temperature  $T_{amb}$ :

 $T_{sp} = T_{amb} + P \times R_{th(sp-a)}$ 

With P being the power dissipation and  $R_{th(sp-a)}$  being the thermal resistance between the solder point and ambient.  $R_{th(sp-a)}$  is determined by the heat transfer properties in the application.

The heat transfer properties are set by the application board materials, the board layout and the environment e.g. housing.



### 9. Characteristics

#### Table 9. Characteristics

 $T_{amb} = 25 \ ^{\circ}C$  unless otherwise specified

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>(BR)CBO</sub>	collector-base breakdown voltage	I <sub>C</sub> = 100 nA; I <sub>E</sub> = 0 mA	24	-	-	V
V <sub>(BR)CEO</sub>	collector-emitter breakdown voltage	$I_{C} = 150 \text{ nA}; I_{B} = 0 \text{ mA}$	12	-	-	V
I <sub>C</sub>	collector current		-	5	30	mA
I <sub>CBO</sub>	collector-base cut-off current	$I_{E} = 0 \text{ mA}; V_{CB} = 8 \text{ V}$	-	<1	-	nA
h <sub>FE</sub>	DC current gain	$I_{C} = 5 \text{ mA}; V_{CE} = 8 \text{ V}$	60	95	200	
Ce	emitter capacitance	V <sub>EB</sub> = 0.5 V; f = 1 MHz	-	0.64	-	pF
C <sub>re</sub>	feedback capacitance	$V_{CE} = 8 V; f = 1 MHz$	-	0.35	-	pF
Cc	collector capacitance	$V_{CB} = 8 V; f = 1 MHz$	-	0.55	-	pF
f <sub>T</sub>	transition frequency	$I_{C}$ = 10 mA; $V_{CE}$ = 8 V; f = 900 MHz	-	10	-	GHz

4 of 22

#### NPN wideband silicon RF transistor

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
G <sub>p(max)</sub>	maximum power gain	f = 433 MHz; V <sub>CE</sub> = 8 V	[1]				
		I <sub>C</sub> = 1 mA		-	16	-	dB
		$I_{\rm C} = 5  \rm{mA}$		-	22.5	-	dB
		I <sub>C</sub> = 10 mA		-	24	-	dB
		f = 900 MHz; V <sub>CE</sub> = 8 V	<u>[1]</u>				
		I <sub>C</sub> = 1 mA		-	13	-	dB
		I <sub>C</sub> = 5 mA		-	18.5	-	dB
		I <sub>C</sub> = 10 mA		-	19.5	-	dB
		f = 1800 MHz; V <sub>CE</sub> = 8 V	<u>[1]</u>				
		I <sub>C</sub> = 1 mA		-	11	-	dB
		I <sub>C</sub> = 5 mA		-	14	-	dB
		I <sub>C</sub> = 10 mA		-	13	-	dB
s <sub>21</sub>   <sup>2</sup>	insertion power gain	f = 433 MHz; V <sub>CE</sub> = 8 V					
		I <sub>C</sub> = 1 mA		-	10.5	-	dB
		$I_{\rm C} = 5  \rm{mA}$		-	20	-	dB
		I <sub>C</sub> = 10 mA		-	22	-	dB
		f = 900 MHz; V <sub>CE</sub> = 8 V					
		I <sub>C</sub> = 1 mA		-	9	-	dB
		$I_{\rm C} = 5  \rm{mA}$		-	15.5	-	dB
		I <sub>C</sub> = 10 mA		-	16.5	-	dB
		f = 1800 MHz; V <sub>CE</sub> = 8 V					
		$I_{\rm C} = 1  {\rm mA}$		-	6	-	dB
		$I_{\rm C} = 5  \rm{mA}$		-	10.5	-	dB
		I <sub>C</sub> = 10 mA		-	11	-	dB
NF <sub>min</sub>	minimum noise figure	f = 433 MHz; $V_{CE}$ = 8 V; $\Gamma_{S}$ = $\Gamma_{opt}$					
		$I_{\rm C} = 1  {\rm mA}$		-	0.5	-	dB
		$I_{\rm C} = 5  \mathrm{mA}$		-	0.7	-	dB
		I <sub>C</sub> = 10 mA		-	0.9	-	dB
		f = 900 MHz; $V_{CE}$ = 8 V; $\Gamma_{S}$ = $\Gamma_{opt}$					
		$I_{\rm C} = 1  {\rm mA}$		-	0.6	-	dB
		$I_{\rm C} = 5  \mathrm{mA}$		-	0.8	-	dB
		I <sub>C</sub> = 10 mA		-	0.9	-	dB
		f = 1800 MHz; $V_{CE}$ = 8 V; $\Gamma_{S}$ = $\Gamma_{opt}$					
		$I_{\rm C} = 1  {\rm mA}$		-	0.8	-	dB
		I <sub>C</sub> = 5 mA		-	0.9	-	dB
		I <sub>C</sub> = 10 mA		-	1.0	-	dB

BFU520W Product data sheet Characteristics ... continued

Table 9.

# **BFU520W**

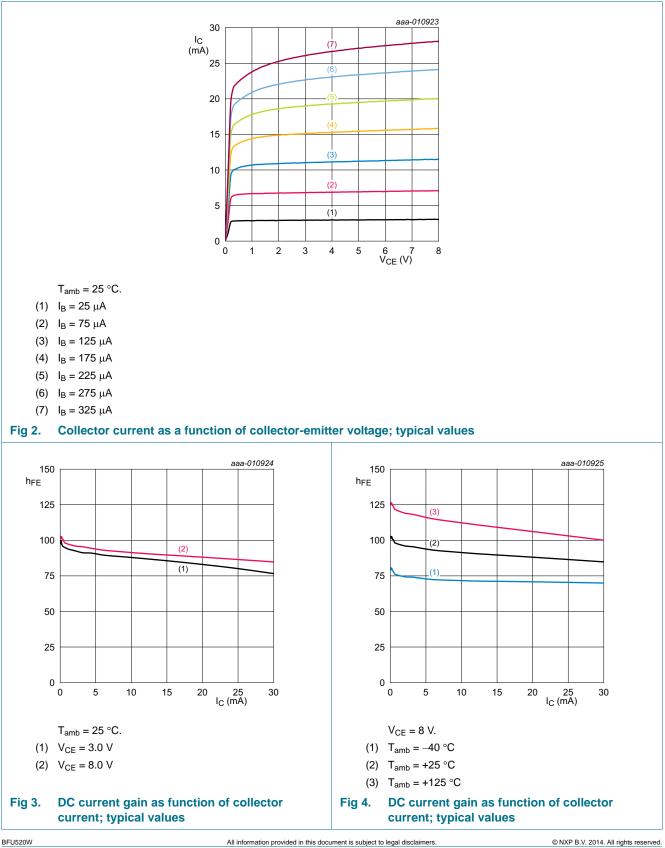
#### NPN wideband silicon RF transistor

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
G <sub>ass</sub>	associated gain	f = 433 MHz; $V_{CE}$ = 8 V; $\Gamma_{S}$ = $\Gamma_{opt}$				
		I <sub>C</sub> = 1 mA	-	24	-	dB
		I <sub>C</sub> = 5 mA	-	23.5	-	dB
		I <sub>C</sub> = 10 mA	-	23.5	-	dB
		f = 900 MHz; $V_{CE}$ = 8 V; $\Gamma_{S}$ = $\Gamma_{opt}$				
		I <sub>C</sub> = 1 mA	-	16	-	dB
		I <sub>C</sub> = 5 mA	-	17	-	dB
		I <sub>C</sub> = 10 mA	-	17.5	-	dB
		f = 1800 MHz; $V_{CE}$ = 8 V; $\Gamma_{S}$ = $\Gamma_{opt}$				
		I <sub>C</sub> = 1 mA	-	9.5	-	dB
		$I_{\rm C} = 5  \rm{mA}$	-	11	-	dB
		I <sub>C</sub> = 10 mA	-	12	-	dB
P <sub>L(1dB)</sub>	output power at 1 dB gain compression	f = 433 MHz; V <sub>CE</sub> = 8 V; Z <sub>S</sub> = Z <sub>L</sub> = 50 $\Omega$				
		$I_{\rm C} = 5  \rm mA$	-	1	-	dBm
		I <sub>C</sub> = 10 mA	-	6	-	dBm
		f = 900 MHz; V <sub>CE</sub> = 8 V; Z <sub>S</sub> = Z <sub>L</sub> = 50 $\Omega$				
		$I_{C} = 5 \text{ mA}$	-	2	-	dBm
		I <sub>C</sub> = 10 mA	-	7	-	dBm
		f = 1800 MHz; V <sub>CE</sub> = 8 V; Z <sub>S</sub> = Z <sub>L</sub> = 50 $\Omega$				
		$I_{C} = 5 \text{ mA}$	-	4	-	dBm
		I <sub>C</sub> = 10 mA	-	8.5	-	dBm
IP3 <sub>o</sub>	output third-order intercept point	f <sub>1</sub> = 433 MHz; f <sub>2</sub> = 434 MHz; V <sub>CE</sub> = 8 V; Z <sub>S</sub> = Z <sub>L</sub> = 50 $\Omega$				
		$I_{C} = 5 \text{ mA}$	-	10	-	dBm
		I <sub>C</sub> = 10 mA	-	16	-	dBm
		$f_1$ = 900 MHz; $f_2$ = 901 MHz; $V_{CE}$ = 8 V; $Z_S$ = $Z_L$ = 50 $\Omega$				
		$I_{\rm C} = 5  \rm{mA}$	-	11	-	dBm
		I <sub>C</sub> = 10 mA	-	17	-	dBm
		$f_1$ = 1800 MHz; $f_2$ = 1801 MHz; V <sub>CE</sub> = 8 V; Z <sub>S</sub> = Z <sub>L</sub> = 50 Ω				
		I <sub>C</sub> = 5 mA	-	14	-	dBm
		l <sub>C</sub> = 10 mA	-	18	-	dBm

 $\label{eq:gamma} \mbox{[1]} \quad \mbox{If } K > 1 \mbox{ then } G_{p(max)} \mbox{ is the maximum power gain. If } K < 1 \mbox{ then } G_{p(max)} \mbox{ = MSG}.$ 

#### NPN wideband silicon RF transistor

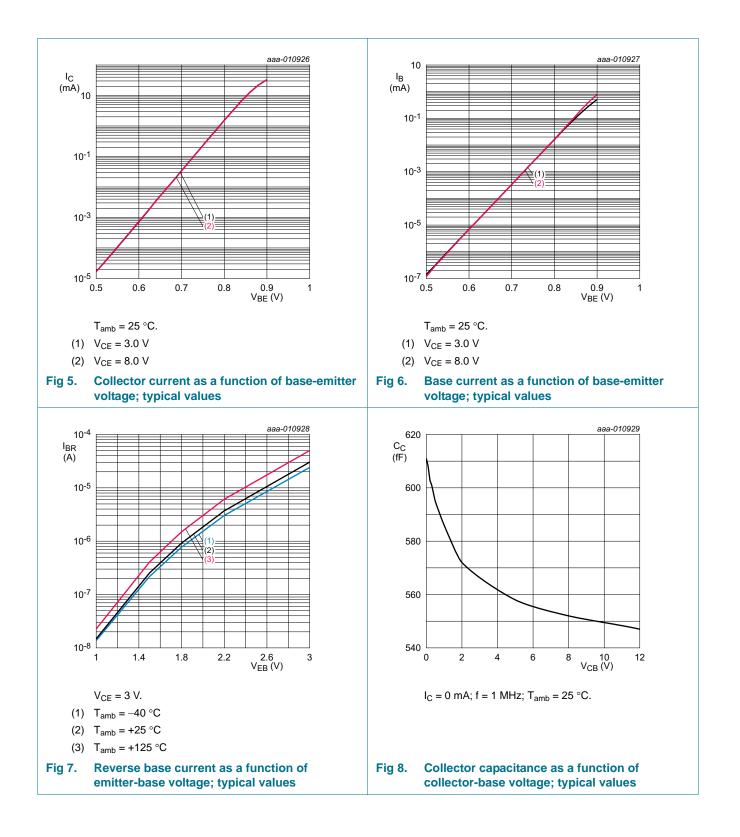




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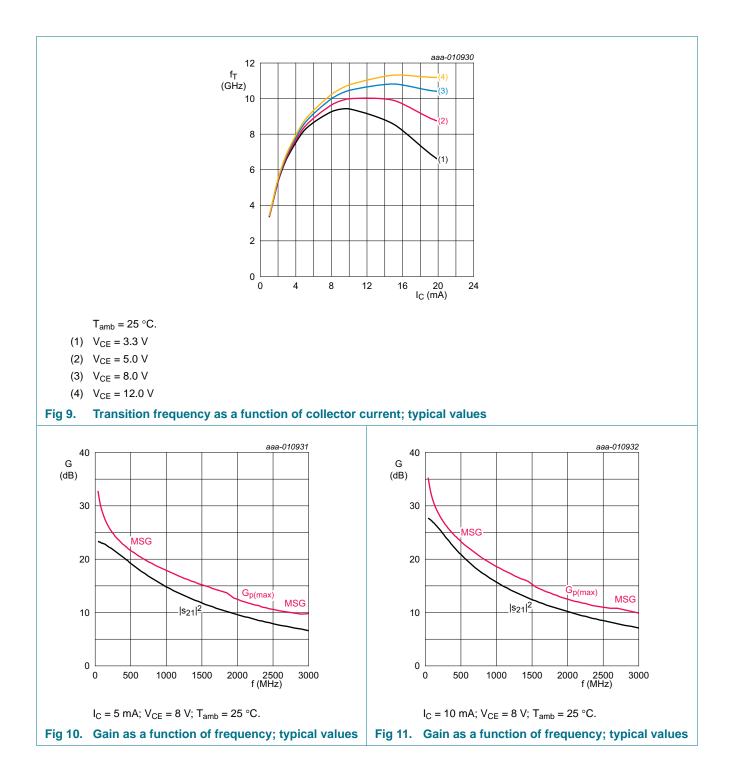
#### NPN wideband silicon RF transistor



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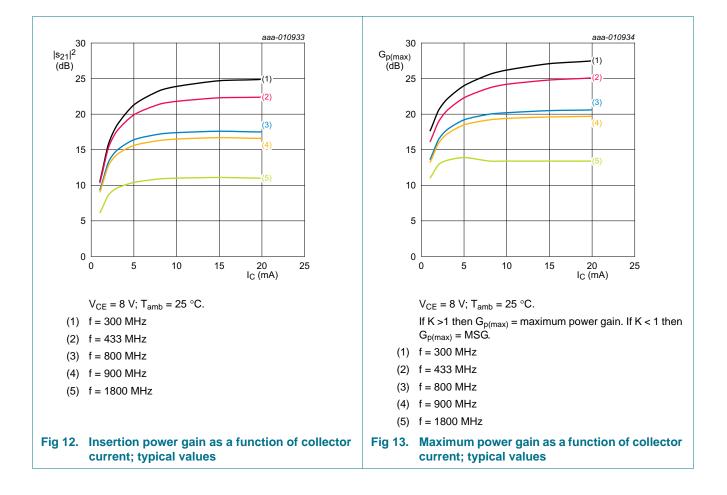
# BFU520W

#### NPN wideband silicon RF transistor



BFU520W Product data sheet

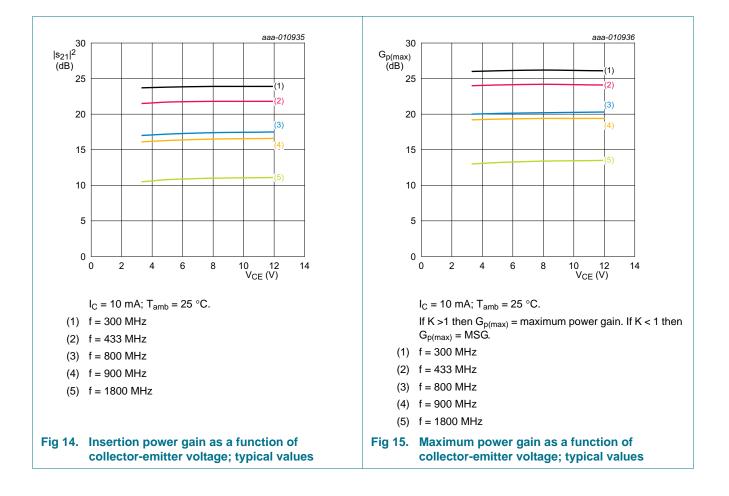
#### NPN wideband silicon RF transistor



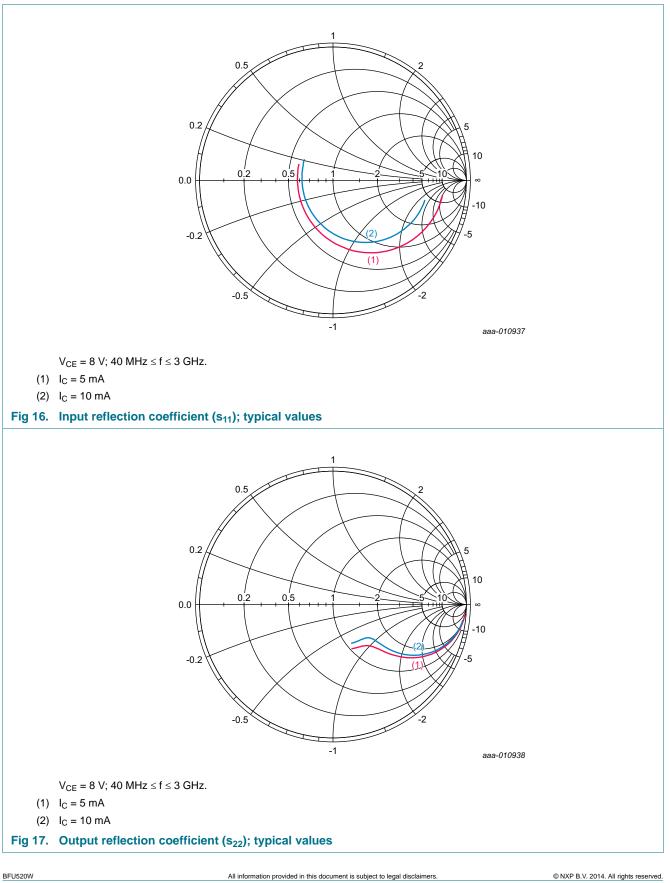
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#### NPN wideband silicon RF transistor



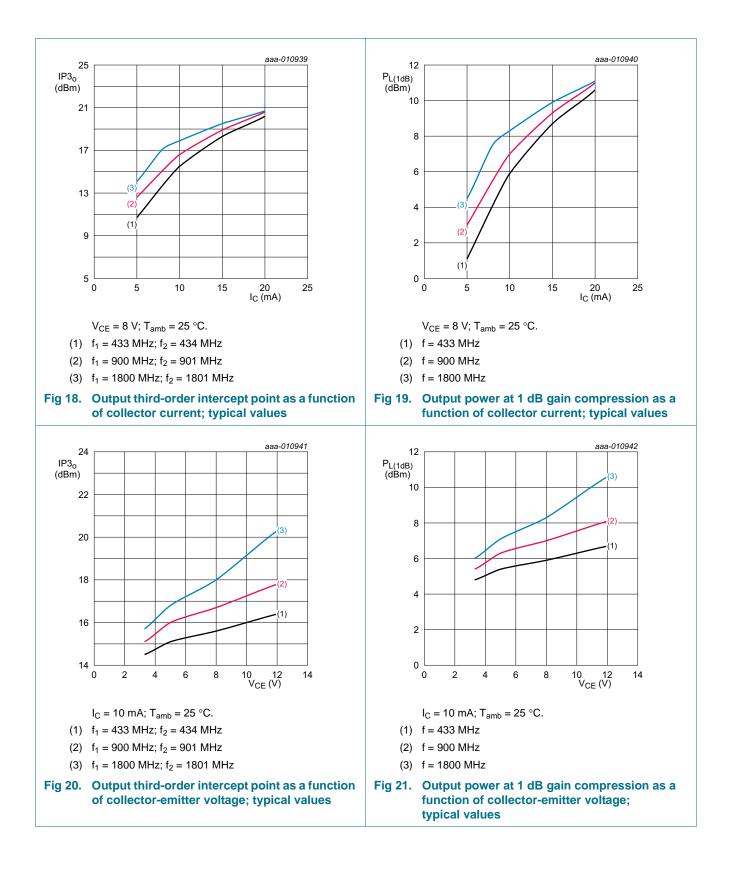
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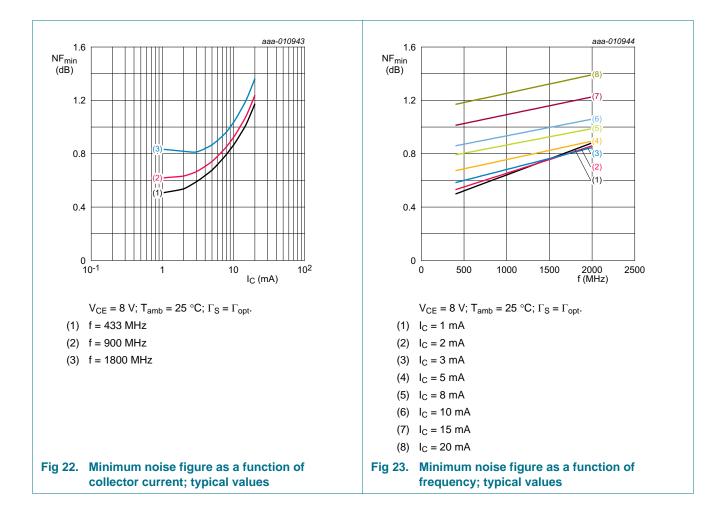
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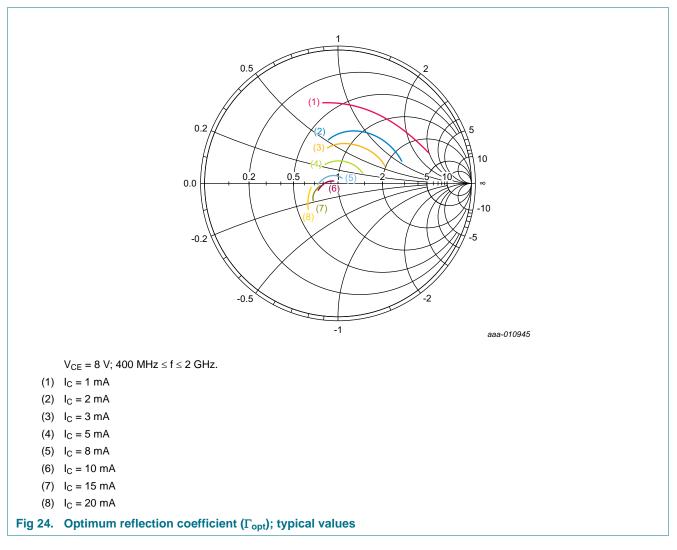
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#### NPN wideband silicon RF transistor



#### NPN wideband silicon RF transistor



### **10.** Application information

More information about the following application example can be found in the application notes. See <u>Section 5 "Design support</u>".

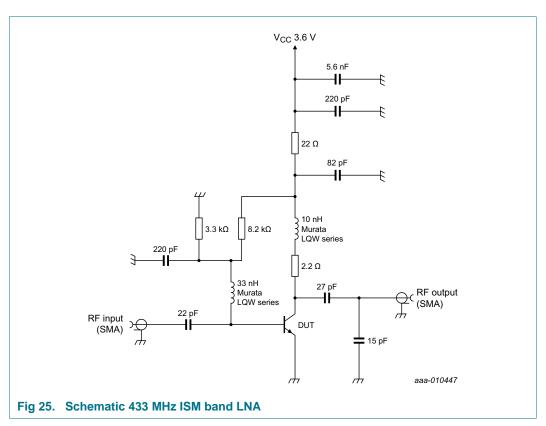
The following application example can be implemented using the evaluation kit. See Section 3 "Ordering information" for the order type number.

The following application example can be simulated using the simulation package. See <u>Section 5 "Design support</u>".

### 10.1 Application example: 433 ISM band LNA

433 ISM band LNA, optimized for low noise.

More detailed information of the application example can be found in the application note: *AN11421*.



# Table 10.Application performance data at 433 MHz $I_{CC} = 7 mA; V_{CC} = 3.6 V$

00						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ s_{21} ^2$	insertion power gain		-	18	-	dB
NF	noise figure		-	1.0	-	dB
IP3 <sub>o</sub>	output third-order intercept point	$f_1$ = 433.1 MHz; $f_2$ = 433.2 MHz; $P_i$ = -30 dBm per carrier	-	11	-	dBm

### 10.2 Application example: 866 ISM band LNA

866 ISM band LNA, optimized for low noise.

More detailed information of the application example can be found in the application note: *AN11422*.

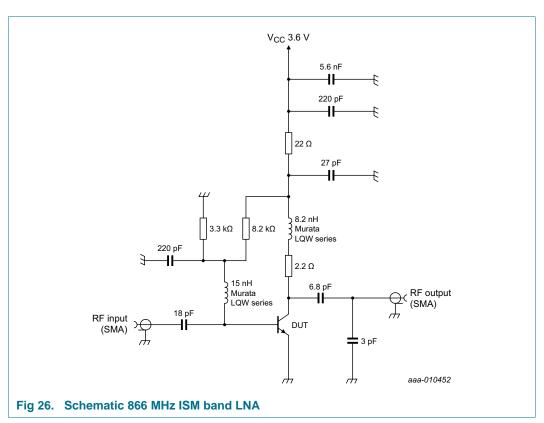
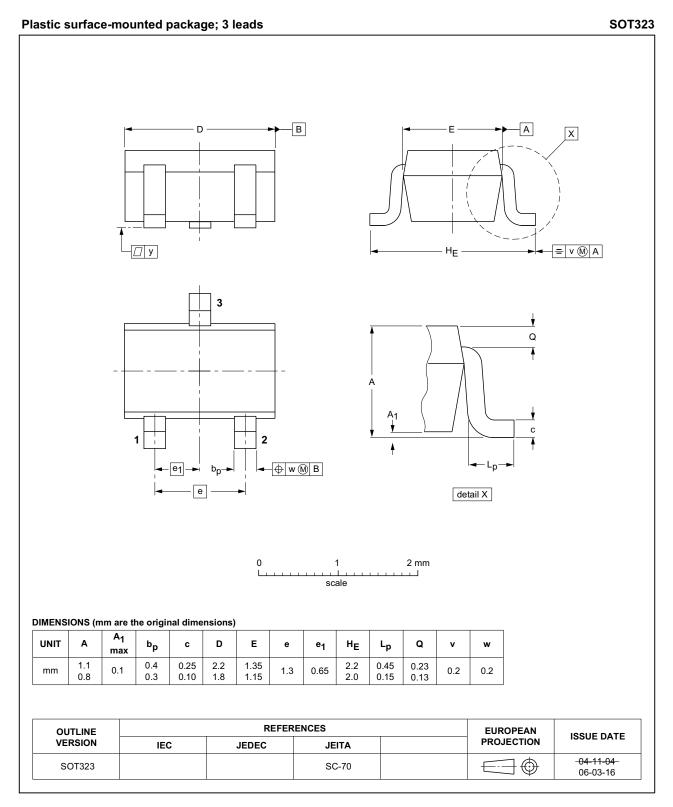


Table 11.Application performance data at 866 MHz $I_{CC} = 7 mA$ ;  $V_{CC} = 3.6 V$ 

00	, 00					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
$ s_{21} ^2$	insertion power gain		-	15	-	dB
NF	noise figure		-	1.1	-	dB
IP3 <sub>o</sub>	output third-order intercept point	$f_1 = 866.1 \text{ MHz}; f_2 = 866.2 \text{ MHz};$ $P_i = -30 \text{ dBm per carrier}$	-	14	-	dBm

NPN wideband silicon RF transistor

## 11. Package outline



#### Fig 27. Package outline SOT323

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## **12. Handling information**

#### CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

### **13. Abbreviations**

Acronym	Description		
AEC	Automotive Electronics Council		
ISM	Industrial, Scientific and Medical		
LNA	Low-Noise Amplifier		
MSG	Maximum Stable Gain		
NPN	Negative-Positive-Negative		
SMA	SubMiniature version A		

## 14. Revision history

Table 13. Revision hist	Revision history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BFU520W v.1	20140113	Product data sheet	-	-

## **15. Legal information**

#### 15.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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#### NPN wideband silicon RF transistor

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### 15.4 Trademarks

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## 16. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com